

Low voltage CMOS 16-bit bus buffer (3-state non inverter) with 3.6 V tolerant inputs and outputs

FLAT-48
The upper metallic lid
is internally connected to
ground



Features

- 1.65 to 3.6 V inputs and outputs
- High speed:
 - $t_{PD} = 3.4$ ns at $V_{CC} = 3.0$ to 3.6 V
 - $t_{PD} = 3.8$ ns at $V_{CC} = 2.3$ to 2.7 V
- Power down protection on inputs and outputs
- Symmetrical output impedance:
 - $|I_{OH}| = I_{OL} = 12$ mA (min.) at $V_{CC} = 3.0$ V
 - $|I_{OH}| = I_{OL} = 8$ mA (min.) at $V_{CC} = 2.3$ V
- 26 Ω serie resistors in outputs
- Operating voltage range:
 - $V_{CC(Opr)} = 1.65$ V to 3.6 V
- Pin and function compatible with 54 series H162244
- Bus hold provided on data inputs
- Cold spare function
- Latch-up performance exceeds 300 mA (JESD 17)
- ESD performance:
 - HBM > 2000 V (Mil Std 883 Method 3015); MM > 200 V
 - 300 krad Mil1019.6 condition A, (RHA QML qualification extension undergone)
- No SEL, no SEU and no SET under 110 Mev/cm²/mg LET heavy ions irradiation
- QML qualified product
- SMD 5962-05210
- 100 mV typical input hysteresis

Product status link

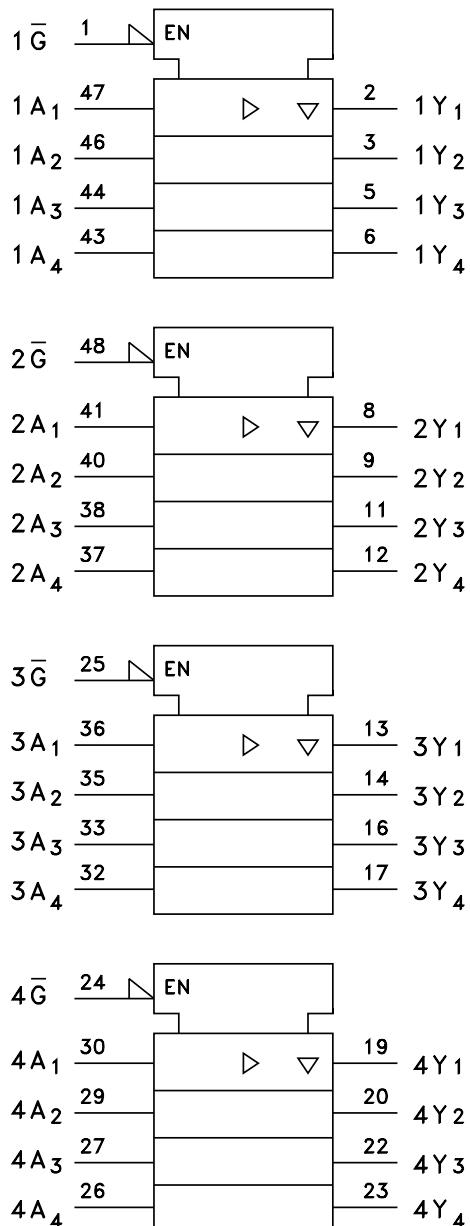
[54VCXH162244](#)

Description

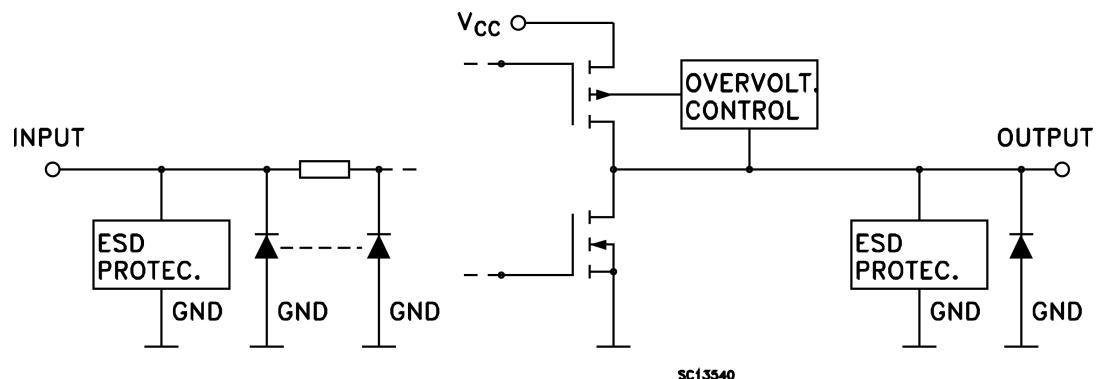
The **54VCXH162244** is a low voltage CMOS 16-bit bus buffer (non inverted) fabricated with submicron silicon gate and five-layer metal wiring C²MOS technology. It is ideal for low power and very high speed 1.65 to 3.6 V applications; it can be interfaced to 3.6 V signal environment for both inputs and outputs. Any nG output control governs four BUS buffers. Output enable input (nG) tied together gives full 16-bit operation. When nG is low, the outputs are on. When nG is high, the output are in high impedance state. This device is designed to be used with 3-state memory address drivers, etc. Bus hold on data inputs is provided in order to eliminate the need for external pull-up or pull-down resistor. The device circuits is including 26 Ω series resistance in the outputs. These resistors permit to reduce line noise in high speed applications. All inputs and outputs are equipped with protection circuits against static discharge, giving them 2 KV ESD immunity and transient excess voltage.

1 Logic symbols and I/O equivalent circuit

Figure 1. IEC logic symbols



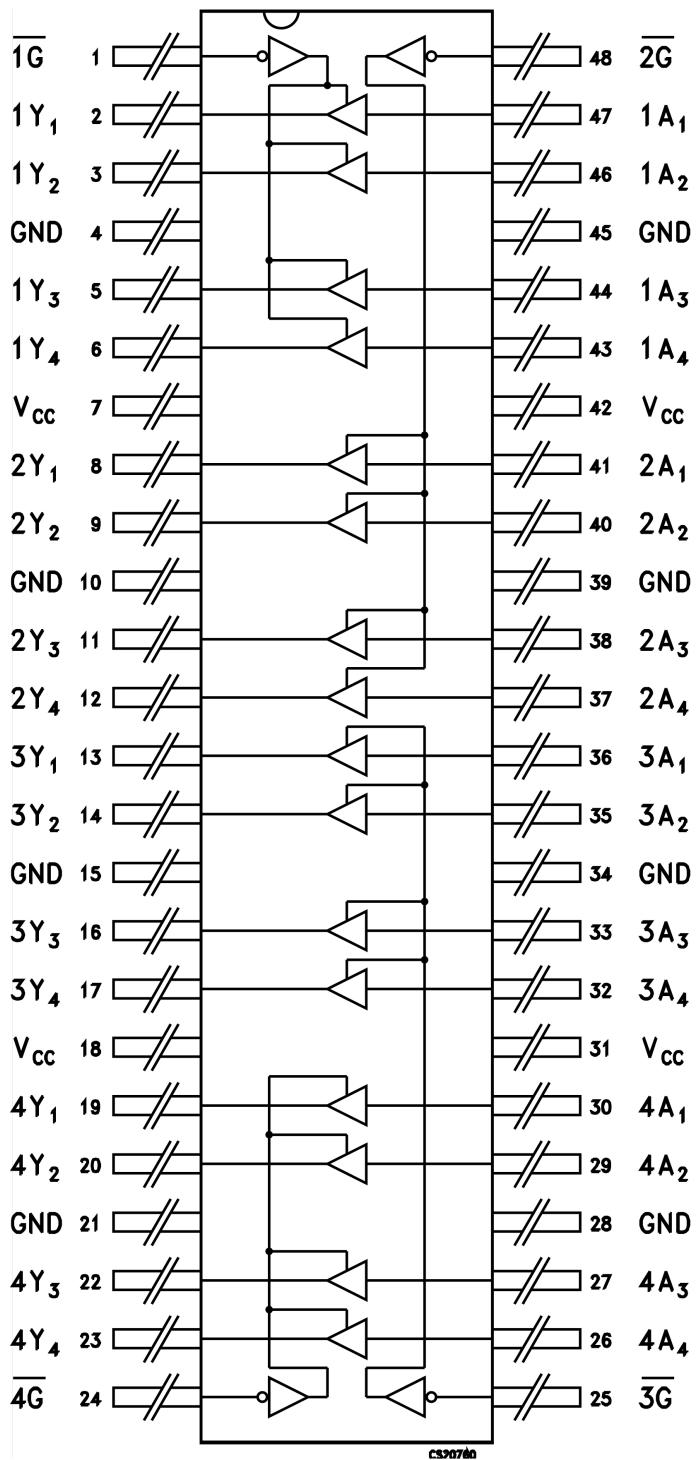
LC13550

Figure 2. Input and output equivalent circuit

2 Pin settings

2.1 Pin connection

Figure 3. Pin connection (top through view)



2.2 Pin description

Table 1. Pin description

| Pin | Symbol | Name and function |
|-------------------------------|------------|-------------------------|
| 1 | $1\bar{G}$ | Output enable input |
| 2, 3, 5, 6 | 1Y1 to 1Y4 | Data outputs |
| 8, 9, 11, 12 | 2Y1 to 2Y4 | Data outputs |
| 13, 14, 16, 17 | 3Y1 to 3Y4 | Data outputs |
| 19, 20, 22, 23 | 4Y1 to 4Y4 | Data outputs |
| 24 | $4\bar{G}$ | Output enable input |
| 25 | $3\bar{G}$ | Output enable input |
| 30, 29, 27, 26 | 4A1 to 4A4 | Data outputs |
| 36, 35, 33, 32 | 3A1 to 3A4 | Data outputs |
| 41, 40, 38, 37 | 2A1 to 2A4 | Data outputs |
| 47, 46, 44, 43 | 1A1 to 1A4 | Data outputs |
| 48 | $2\bar{G}$ | Output enable input |
| 4, 10, 15, 21, 28, 34, 39, 45 | GND | Ground (0 V) |
| 7, 18, 31, 42 | VCC | Positive supply voltage |

2.3 Truth table

Table 2. Truth table

| Inputs | | Outputs |
|--------|----|---------|
| G | An | Yn |
| L | L | L |
| L | H | H |
| H | X | Z |

X = do not care; Z = high impedance

3

Maximum ratings

Stressing the device above the rating listed in the “absolute maximum ratings” table may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the operating sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 3. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|-----------------------|--|------------------------|------|
| V_{CC} | Supply voltage | -0.5 to +4.6 | V |
| V_I | DC input voltage | -0.5 to +4.6 | V |
| V_O | DC output voltage (OFF-state) ⁽¹⁾ | -0.5 to +4.6 | V |
| V_O | DC output voltage (high or low-state) | -0.5 to $V_{CC} + 0.5$ | V |
| I_{IK} | DC input diode current | -50 | mA |
| I_{OK} | DC output diode current ⁽²⁾ | -50 | mA |
| I_O | DC output current | ± 50 | mA |
| I_{CC} or I_{GND} | DC V_{CC} or ground current per supply pin | ± 100 | mA |
| P_D | Power dissipation | 400 | mW |
| T_{stg} | Storage temperature | -65 to +150 | °C |
| T_L | Lead temperature (10 s) | 260 | °C |
| R_{thjc} | Thermal resistance junction-to-case ⁽³⁾ | 22 | °C/W |
| ESD | HBM: human body model ⁽⁴⁾ | 2 | kV |

1. I_O absolute maximum rating must be observed.
2. $V_O < GND$, $V_O > V_{CC}$.
3. Short-circuits can cause excessive heating and destructive dissipation. Values are typical.
- 4.) Human body model: a 100 pF capacitor is charged to the specified voltage, then discharged through a 1.5 kΩ resistor between two pins of the device. This is done for all couples of connected pin combinations while the other pins are floating.

3.1 Recommended conditions

Table 4. Recommended operating conditions

| Symbol | Parameter | Value | Unit |
|-----------------------------------|---|----------------------|------|
| V _{CC} | Supply voltage | 1.8 to 3.6 | V |
| V _I | Input voltage | -0.3 to 3.6 | V |
| V _O | Output voltage (OFF-state) | 0 to 3.6 | V |
| V _O | Output voltage (high or low-state) | 0 to V _{CC} | V |
| I _{OH} , I _{OL} | High or low level output current (V _{CC} = 3.0 to 3.6 V) | ± 12 | mA |
| I _{OH} , I _{OL} | High or low level output current (V _{CC} = 2.3 to 2.7 V) | ± 8 | mA |
| T _{op} | Operating temperature | -55 to 125 | °C |
| dt/dv | Input rise and fall time ⁽¹⁾ | 0 to 10 | ns/V |

1. V_{IN} from 0.8 V to 2 V at $V_{CC} = 3.0$ V.

4
Electrical characteristics
Table 5. DC specifications

| Symbol | Parameter | Test conditions | | Value | | Unit | |
|-----------------|---------------------------------------|-----------------|---|---------------|------|---------|--|
| | | V_{CC} (V) | | -55 to 125 °C | | | |
| | | | | Min. | Max. | | |
| V_{IH} | High level input voltage | 2.7 to 3.6 | | 2.0 | | V | |
| V_{IL} | Low level input voltage | | | | 0.8 | | |
| V_{OH} | High level output voltage | 2.7 to 3.6 | $I_O = -100 \mu A$ | $V_{CC}-0.2$ | | V | |
| | | 2.7 | $I_O = -6 mA$ | 2.2 | | | |
| | | 3.0 | $I_O = -8 mA$ | 2.4 | | | |
| | | | $I_O = -12 mA$ | 2.2 | | | |
| V_{OL} | Low level output voltage | 2.7 to 3.6 | $I_O = 100 \mu A$ | 0.2 | | V | |
| | | 2.7 | $I_O = 6 mA$ | 0.4 | | | |
| | | 3 | $I_O = 8 mA$ | 0.5 | | | |
| | | | $I_O = 12 mA$ | 0.8 | | | |
| I_I | Input leakage current | 2.7 to 3.6 | $V_I = V_{CC}$ or GND | ± 5 | | μA | |
| $I_{I(HOLD)}$ | Input hold current | 3 | $V_I = 0.8 V$ | 75 | | μA | |
| | | | $V_I = 2 V$ | -75 | | | |
| | | 3.6 | $V_I = 0$ to 3.6 V | ± 500 | | | |
| I_{off} | Power off leakage current | 0 | V_I or $V_O = 0$ to 3.6 V | 10 | | μA | |
| I_{OZ} | High impedance output leakage current | 2.7 to 3.6 | $V_I = V_{IH}$ or V_{IL} , $V_O = 0$ to 3.6 V | ± 10 | | μA | |
| I_{CC} | Quiescent supply current | 2.7 to 3.6 | $V_I = V_{CC}$ or GND | 20 | | μA | |
| | | | V_I or $V_O = V_{CC}$ to 3.6 V | ± 20 | | μA | |
| ΔI_{CC} | I_{CC} incr. per input | 2.7 to 3.6 | $V_{IH} = V_{CC} - 0.6 V$ | 750 | | μA | |

Table 6. DC specifications

| Symbol | Parameter | Test conditions | | Value | | Unit | |
|----------|---------------------------|-----------------|--------------------|---------------|------|------|--|
| | | V_{CC} (V) | | -55 to 125 °C | | | |
| | | | | Min. | Max. | | |
| V_{IH} | High level input voltage | 2.3 to 2.7 | | 1.6 | | V | |
| V_{IL} | Low level input voltage | | | | 0.7 | | |
| V_{OH} | High level output voltage | 2.3 to 2.7 | $I_O = -100 \mu A$ | $V_{CC}-0.2$ | | V | |
| | | 2.3 | $I_O = -4 mA$ | 2.0 | | | |
| | | | $I_O = -6 mA$ | 1.8 | | | |
| | | | $I_O = -8 mA$ | 1.7 | | | |

| Symbol | Parameter | Test conditions | | Value | | Unit | |
|-------------|---------------------------------------|-----------------|--|---------------|----------|---------|--|
| | | V_{CC} (V) | | -55 to 125 °C | | | |
| | | | | Min. | Max. | | |
| V_{OL} | Low level output voltage | 2.3 to 2.7 | $I_O = 100 \mu A$ | | 0.2 | V | |
| | | 2.3 | $I_O = 6 mA$ | | 0.4 | | |
| | | 3 | $I_O = 8 mA$ | | 0.6 | | |
| I_I | Input leakage current | 2.3 to 2.7 | $V_I = V_{CC}$ or GND | | ± 5 | μA | |
| I_{IHOLD} | Input hold current | 2.3 | $V_I = 0.7 V$ | 45 | | μA | |
| | | | $V_I = 1.7 V$ | -45 | | | |
| I_{off} | Power off leakage current | 0 | V_I or $V_O = 0$ to 3.6 V | | 10 | μA | |
| I_{OZ} | High impedance output leakage current | 2.3 to 2.7 | $V_I = V_{IH}$ or $V_{IL}, V_O = 0$ to 3.6 V | | ± 10 | μA | |
| I_{CC} | Quiescent supply current | 2.3 to 2.7 | $V_I = V_{CC}$ or GND | | 20 | μA | |
| | | | V_I or $V_O = V_{CC}$ to 3.6 V | | ± 20 | μA | |

Table 7. Dynamic switching characteristics ($T_A = 25$ °C, input $t_r = t_f = 2.0$ ns, $C_L = 30$ pF, $R_L = 500 \Omega$)

| Symbol | Parameter | Test conditions | | Value | | Unit |
|-----------|--|-----------------|---------------------------------|---------------|--|------|
| | | V_{CC} (V) | | $T_A = 25$ °C | | |
| V_{OLP} | Dynamic low voltage quiet output ⁽¹⁾⁽²⁾ | 2.5 | $V_{IL} = 0 V, V_{IH} = V_{CC}$ | 0.25 | | V |
| | | 3.3 | | 0.35 | | |
| V_{OL} | Dynamic low voltage quiet output ^{(1), (2)} | 2.5 | $V_{IL} = 0 V, V_{IH} = V_{CC}$ | -0.25 | | V |
| | | 3.3 | | -0.35 | | |
| V_{OHV} | Dynamic high voltage quiet output ⁽²⁾⁽³⁾ | 2.5 | $V_{IL} = 0 V, V_{IH} = V_{CC}$ | 2.05 | | V |
| | | 3.3 | | 2.65 | | |

1. Number of outputs defined as "n". Measured with "n-1" output switching from HIGH to LOW or LOW to HIGH. The remaining output is measured in the LOW state.
2. Parameters guaranteed by design.
3. Number of outputs defined as "n". Measured with "n-1" outputs switching from HIGH to LOW or LOW to HIGH. The remaining output is measured in the HIGH state.

Table 8. AC electrical characteristics ($C_L = 30$ pF, $R_L = 500 \Omega$, Input $t_r = t_f = 2.0$ ns)

| Symbol | Parameter | Test conditions | | Value | | Unit | |
|--------------------|------------------------|-----------------|--|---------------|------|------|--|
| | | V_{CC} (V) | | -55 to 125 °C | | | |
| | | | | Min. | Max. | | |
| t_{PLH}, t_{PHL} | Propagation delay time | 2.3 to 2.7 | | 1.0 | 5.2 | ns | |
| | | 3.0 to 3.6 | | 0.8 | 5.0 | | |
| t_{PZL}, t_{PZH} | Output enable time | 2.3 to 2.7 | | 1.0 | 5.8 | ns | |
| | | 3.0 to 3.6 | | 0.8 | 4.2 | | |
| t_{PLZ}, t_{PHZ} | Output disable time | 2.3 to 2.7 | | 1.0 | 4.5 | ns | |
| | | 3.0 to 3.6 | | 0.8 | 4.0 | | |

| Symbol | Parameter | Test conditions | | Value | | Unit | |
|---------------------------------------|---|---------------------|---------------|-------|----|------|--|
| | | V _{CC} (V) | -55 to 125 °C | | | | |
| | | | Min. | Max. | | | |
| t _{OSLH} , t _{OSSH} | Output to output skew time ^{(1) (2)} | 2.3 to 2.7 | | 0.5 | ns | | |
| | | 3.0 to 3.6 | | 0.5 | | | |

1. Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs of the same device switching in the same direction, either HIGH or LOW ($t_{OSLH} = |t_{PLHm} - t_{PLHn}|$, $t_{OSSH} = |t_{PHLm} - t_{PHLn}|$).
2. Parameter guaranteed by design.

Table 9. Capacitive characteristics

| Symbol | Parameter | Test conditions | | Value | Unit |
|------------------|--|---------------------|--|-------|------|
| | | V _{CC} (V) | T _A = 25 °C | | |
| C _{IN} | Input capacitance | 2.5 or 3.3 | V _{IN} = 0 or V _{CC} | 6 | pF |
| C _{OUT} | Output capacitance | 2.5 or 3.3 | f _{IN} = 10 MHz | 7 | pF |
| C _{PD} | Power dissipation capacitance ⁽¹⁾ | 2.5 or 3.3 | V _{IN} = 0 or V _{CC} | 20 | pF |

1. CPD is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to test circuit). Average operating current can be obtained by the following equation.
 $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/16$ (per circuit).

5 Test circuit

Figure 4. Application circuit

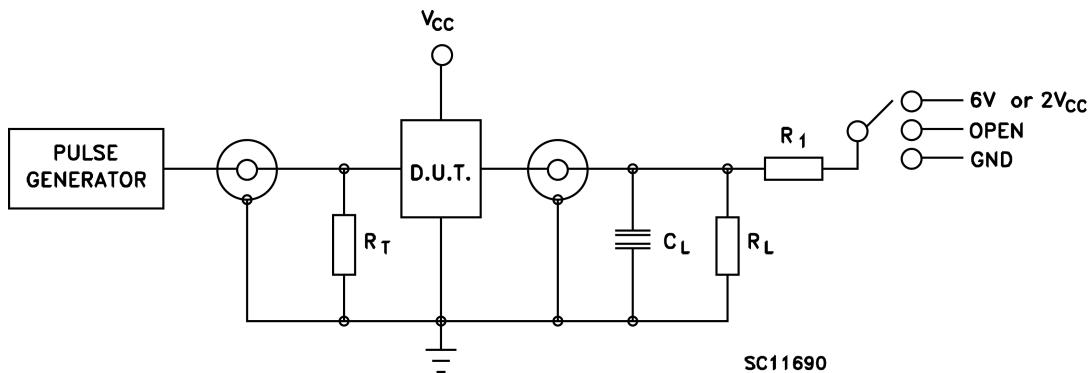


Table 10. Test circuit

| Test | Switch |
|---|-------------------|
| t_{PLH}, t_{PHL} | Open |
| $t_{PZL}, t_{PLZ} (V_{CC} = 3.0 \text{ to } 3.6 \text{ V})$ | 6 V |
| $t_{PZL}, t_{PLZ} (V_{CC} = 2.3 \text{ to } 2.7 \text{ V})$ | 2 V _{CC} |
| t_{PZH}, t_{PHZ} | GND |

$C_L = 10/30 \text{ pF}$ or equivalent (includes jig and probe capacitance)

$R_L = R_1 = 500 \Omega$ or equivalent

$R_T = Z_{OUT}$ of pulse generator (typically 50 Ω)

6 Waveforms

Table 11. Waveform symbol value

| Symbol | V _{CC} | |
|-----------------|------------------------|-------------------------|
| | 3.0 to 3.6 V | 2.3 to 2.7 V |
| V _{IH} | 2.7 V | V _{CC} |
| V _M | 1.5 V | V _{CC} /2 |
| V _X | V _{OL} +0.3 V | V _{OL} +0.15 V |
| V _Y | V _{OH} -0.3 V | V _{OH} -0.15 V |

Figure 5. Waveform - propagation delay (f = 1 MHz; 50% duty cycle)

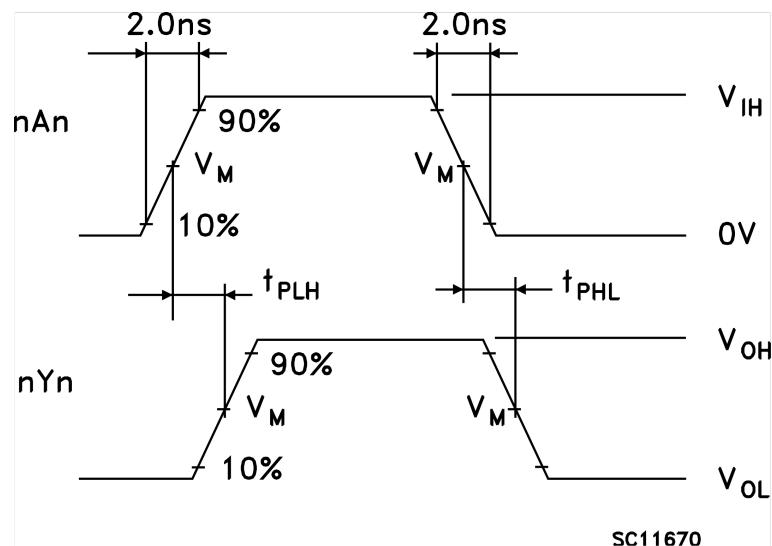
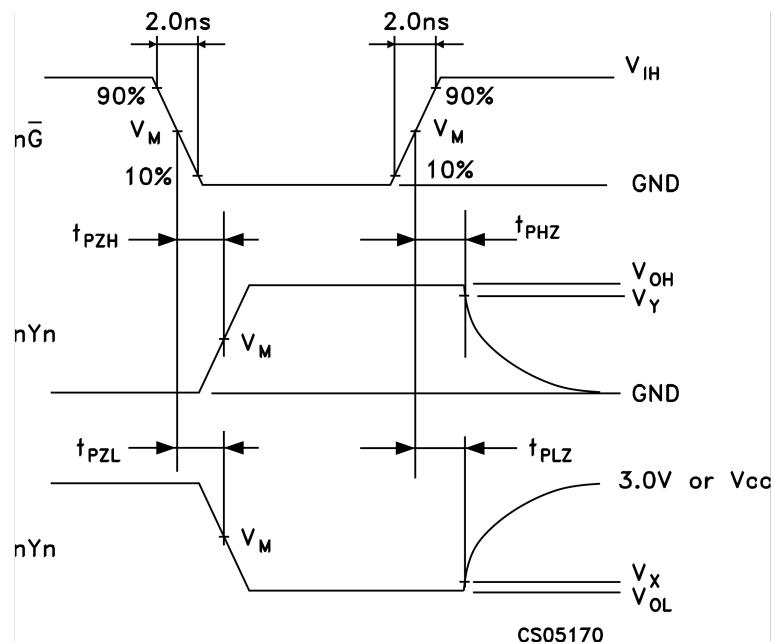


Figure 6. Waveform - output enable and disable time ($f = 1$ MHz; 50% duty cycle)

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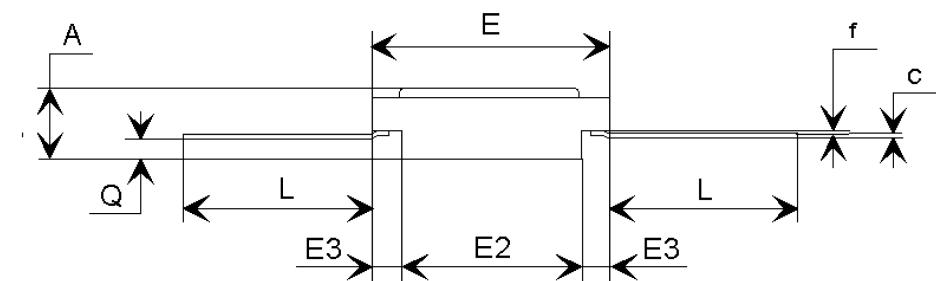
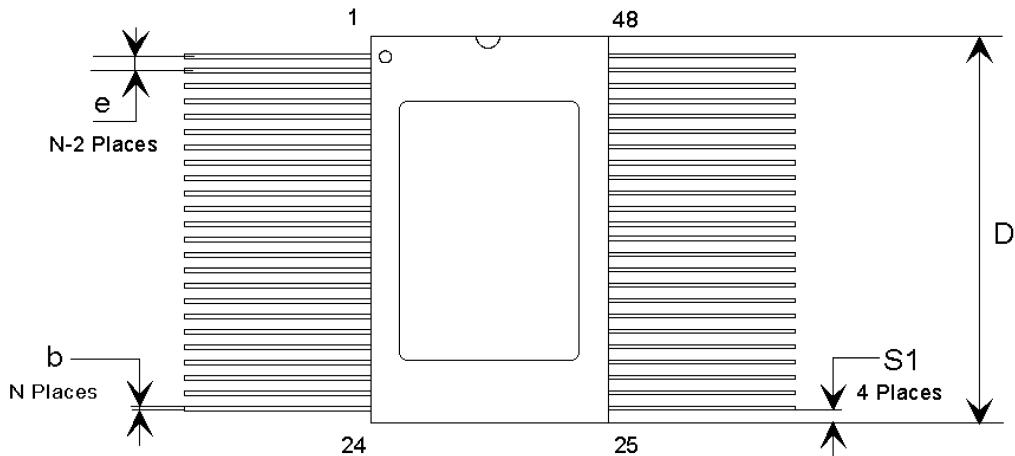
Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

7.1

FLAT-48 package information

Figure 7. FLAT-48 package outline



Note: The upper metallic lid is internally connected to ground

Table 12. FLAT-48 package mechanical data

| Symbol | mm | | | Inches ⁽¹⁾ | | |
|--------|-------|-------|-------|-----------------------|------|------|
| | Min. | Typ. | Max. | Min. | Typ. | Max. |
| A | 2.18 | 2.47 | 2.72 | .086 | .097 | .107 |
| b | 0.20 | 0.254 | 0.30 | .008 | .010 | .012 |
| c | 0.12 | 0.15 | 0.18 | .005 | .006 | .007 |
| D | 15.57 | 15.75 | 15.92 | .613 | .620 | .627 |
| E | 9.52 | 9.65 | 9.78 | .375 | .380 | .385 |
| E2 | 6.22 | 6.35 | 6.48 | .245 | .250 | .255 |
| E3 | 1.52 | 1.65 | 1.78 | .060 | .065 | .070 |
| e | | 0.635 | | | .025 | |
| f | | 0.20 | | | .008 | |
| L | 6.85 | 8.38 | 9.40 | .270 | .330 | .370 |
| Q | 0.66 | 0.79 | 0.92 | .026 | .031 | .036 |
| S1 | 0.25 | 0.43 | 0.61 | .010 | .017 | .024 |

1. Values in inches are converted from mm and rounded to 4 decimal digits.

8

Ordering information

| Order code | SMD ⁽¹⁾ | Qualification level | Mass | Package | Lead finish | Marking ⁽²⁾ | Packing |
|-----------------|--------------------|---------------------|-------|---------|-------------|------------------------|-----------------------|
| RHFXH162244K1 | - | Engineering model | 1.5 g | Flat-48 | Gold | RHFXH162244K1 | Conductive strip pack |
| RHFXH162244K03V | 5962F05210 | QML-V Flight | | | | 5962F0521002VXC | |

1. Standard microcircuit drawing

2. Specific marking only. Complete marking includes the following:

- ST logo
- Date code (date the package was sealed) in YYWWA (year, week, and lot index of week)
- Country of origin (FR = France)

Other information

Date code:

The date code is structured as engineering model: EM xyywwz

Where:

x = 3 (EM only), assembly location Rennes (France)

yy = last two digits of the year

ww = week digits

z = lot index of the week

Product documentation

Each product shipment includes a set of associated documentation within the shipment box. This documentation depends on the quality level of the products, as detailed in the table below.

The certificate of conformance is provided on paper whatever the quality level. For QML parts, complete documentation, including the certificate of conformance, is provided on a CDROM.

Table 13. Product documentation

| Quality level | Item |
|-------------------|---|
| Engineering model | Certificate of conformance including : Customer name Customer purchase order number ST sales order number and item ST part number Quantity delivered Date code Reference to ST datasheet Reference to TN1181 on engineering models ST Rennes assembly lot ID |

| Quality level | Item |
|---------------|---|
| QML-V Flight | Certificate of Conformance including: Customer name Customer purchase order number ST sales order number and item ST part number Quantity delivered Date code Serial numbers Group C reference Group D reference Reference to the applicable SMD ST Rennes assembly lot ID |
| | Quality control inspection (groups A, B, C, D, E) |
| | Screening electrical data in/out summary |
| | Precap report |
| | PIND (particle impact noise detection) test |
| | SEM (scanning electronic microscope) inspection report |
| | X-ray plates |
| | |
| | |
| | |

Revision history

Table 14. Document revision history

| Date | Version | Changes |
|-------------|---------|---|
| 09-Jul-2004 | 1 | Initial release. |
| 17-May-2005 | 2 | SMD qualified |
| 19-Jun-2006 | 3 | 300 krad bullet updated, new template, mechanical data updated |
| 11-Apr-2007 | 4 | Updated cover page features |
| 30-Jul-2007 | 5 | Typo in Table 12 on page 14 |
| 17-Sep-2008 | 6 | Updated cover page |
| 09-Jan-2009 | 7 | Updated cover page |
| 23-Sep-2009 | 8 | Updated Table 13 on page 16 |
| 29-Jul-2011 | 9 | Added Note: on page 15 and in the "Pin connections" diagram on the cover page. |
| 11-Jun-2019 | 10 | Updated cover image, Section 7.1 FLAT-48 package information and Section 8 Ordering information . |

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